



30V P-Channel MOSFETs

General Description

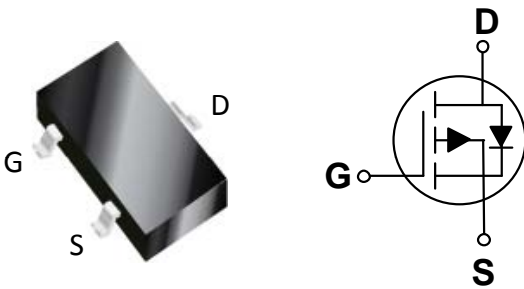
These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BV_{DSS}	$R_{DS(ON)}$	I_D
-30 V	32 mΩ	-4.8 A

Features

- -30V, -4.8A, $R_{DS(ON)}=32m\Omega @V_{GS}= -10V$
- Fast switching
- Green Device Available
- Suit for -2.5V Gate Drive Applications
- RoHS compliant & Halogen Free

SOT-23 Pin Configuration



Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-Held Instruments

Absolute Maximum Ratings $T_c=25^\circ C$ unless otherwise noted

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-30	V
V_{GS}	Gate-Source Voltage	±12	V
I_D	Drain Current - Continuous ($T_A=25^\circ C$)	-4.8	A
	Drain Current - Continuous ($T_A=70^\circ C$)	-3.8	A
I_{DM}	Drain Current - Pulsed (NOTE 1)	-19.2	A
P_D	Power Dissipation ($T_A=25^\circ C$)	1	W
	Power Dissipation - Derate above $25^\circ C$	0.008	W/°C
T_J	Operating Junction Temperature Range	-50 to 150	°C
T_{STG}	Storage Temperature Range	-50 to 150	°C
Marking Code		h	

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to Ambient	---	125	°C/W



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Electrical Characteristics ($T_J=25^{\circ}\text{C}$, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=-250\mu\text{A}$	-30	---	---	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=-30\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^{\circ}\text{C}$	---	---	-1	μA
		$V_{DS}=-24\text{V}$, $V_{GS}=0\text{V}$, $T_J=125^{\circ}\text{C}$	---	---	-10	μA
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 12\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA

On Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-10\text{V}$, $I_D=-2\text{A}$	---	26	32	m Ω
		$V_{GS}=-4.5\text{V}$, $I_D=-1\text{A}$	---	30	38	
		$V_{GS}=-2.5\text{V}$, $I_D=-0.5\text{A}$	---	37	48	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=-250\mu\text{A}$	-0.5	-0.7	-1.0	V
gfs	Forward Transconductance	$V_{DS}=-10\text{V}$, $I_D=-1\text{A}$	---	5.5	---	S

Dynamic and switching Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Q_g	Total Gate Charge	$V_{DS}=-15\text{V}$, $V_{GS}=-10\text{V}$, $I_D=-2\text{A}$ (NOTE 2、3)	---	31	62	nC
Q_{gs}	Gate-Source Charge		---	1.4	3	
Q_{gd}	Gate-Drain Charge		---	4.6	9	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=-15\text{V}$, $V_{GS}=-10\text{V}$, $R_G=6\Omega$, $I_D=-1\text{A}$ (NOTE 2、3)	---	7.9	16	nS
T_r	Rise Time		---	13.2	26	
$T_{d(off)}$	Turn-Off Delay Time		---	38.6	76	
T_f	Fall Time		---	12.5	25	
C_{iss}	Input Capacitance	$V_{DS}=-15\text{V}$, $V_{GS}=0\text{V}$, $F=1\text{MHz}$	---	1540	3000	pF
C_{oss}	Output Capacitance		---	142	280	
C_{riss}	Reverse Transfer Capacitance		---	118	240	

Drain-Source Diode Characteristics and Ratings

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_S	Continuous Source Current	$V_G=V_D=0\text{V}$, Force Current	---	---	-4.8	A
I_{SM}	Pulsed Source Current		---	---	-9.6	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0\text{V}$, $I_S=-1\text{A}$, $T_J=25^{\circ}\text{C}$	---	---	-1	V

NOTES :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. Essentially independent of operating temperature.



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Characteristics Curves

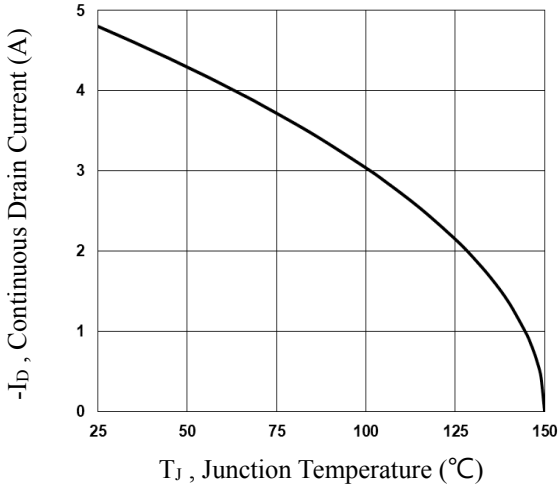


Fig.1 Continuous Drain Current vs. T_J

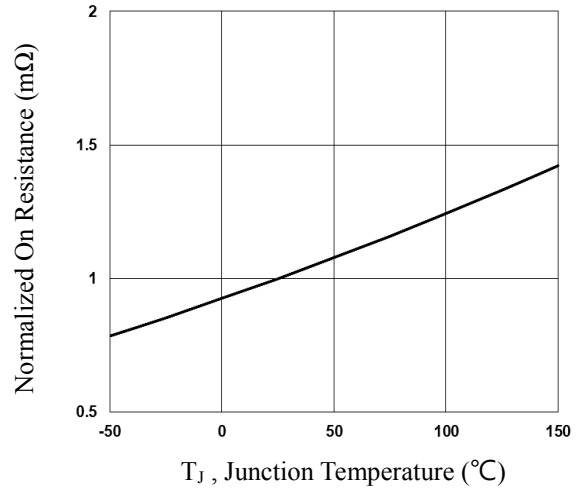


Fig.2 Normalized $R_{DS(ON)}$ vs. T_J

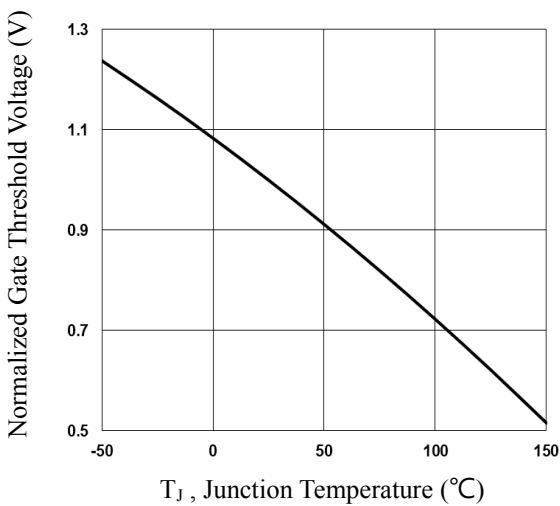


Fig.3 Normalized V_{th} vs. T_J

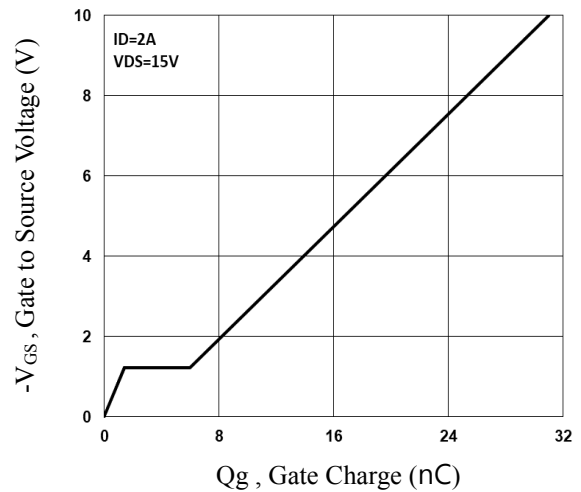


Fig.4 Gate Charge Waveform

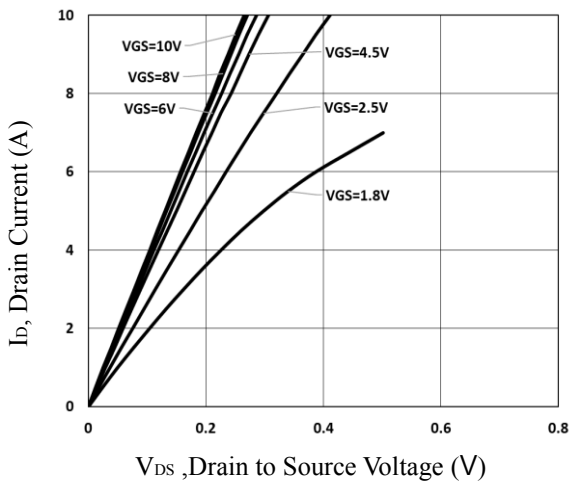


Fig.5 Typical Output Characteristics

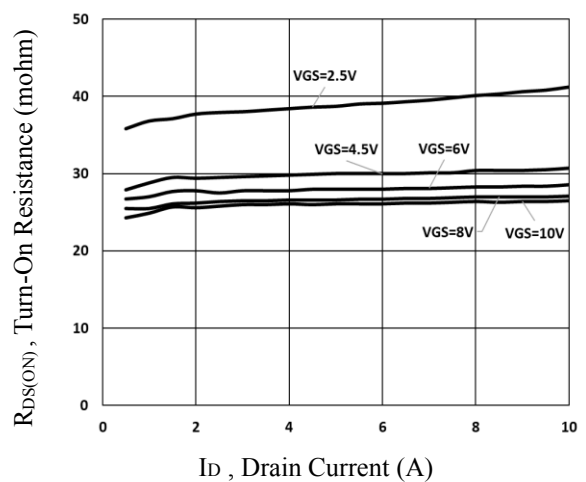


Fig.6 Turn-On Resistance vs. I_D



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Characteristics Curves

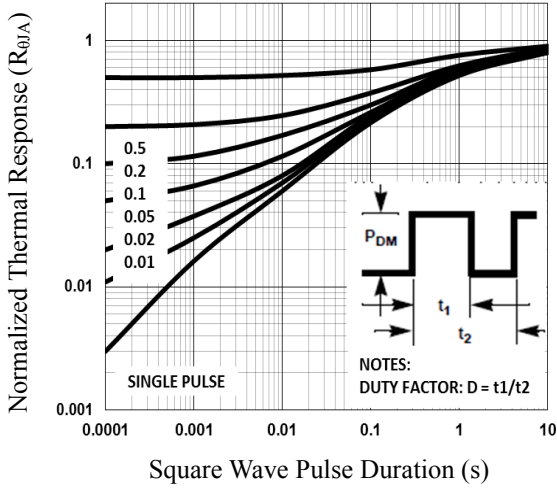


Fig.7 Normalized Transient Impedance

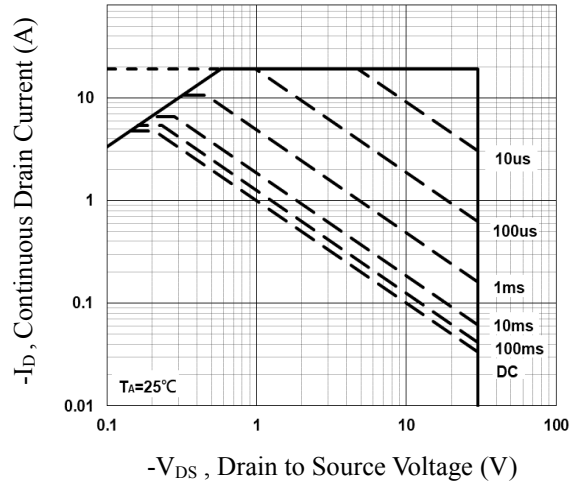


Fig.8 Maximum Safe Operation Area

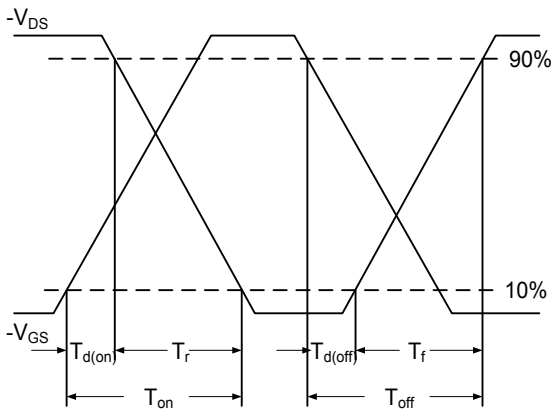


Fig.9 Switching Time Waveform

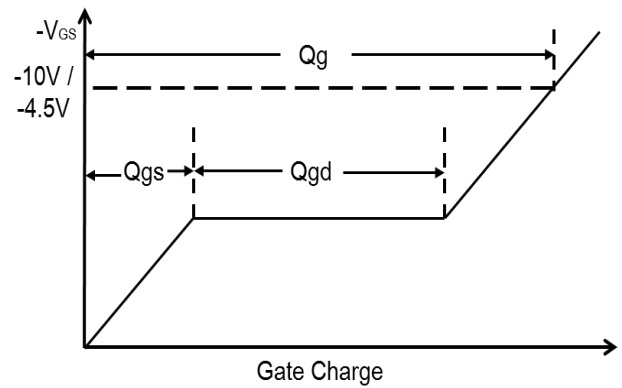
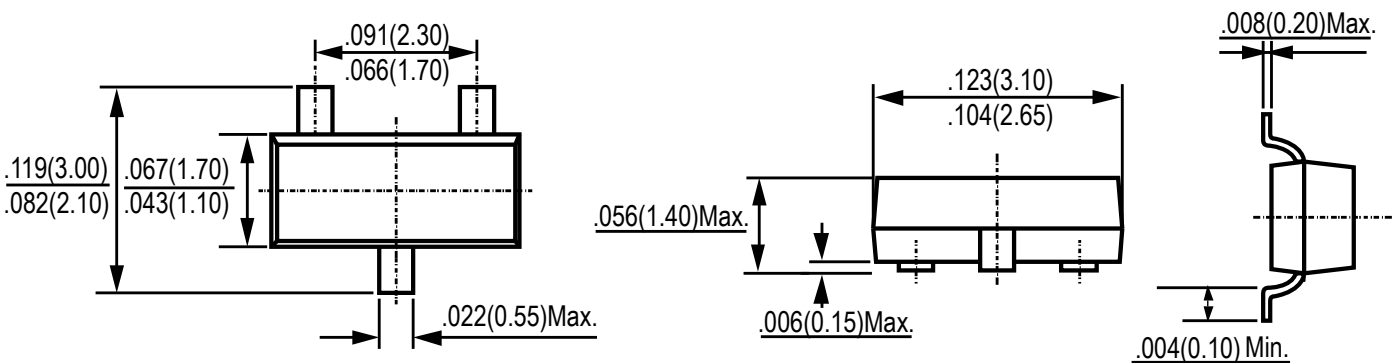


Fig.10 Gate Charge Waveform

Package Outline Dimensions



SOT-23

Dimensions in inches and (millimeters)



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